


<b>Search Notes</b>  	<b>Application/Control No.</b>  10511734	<b>Applicant(s)/Patent Under Reexamination</b>  PROTIC ET AL.
	<b>Examiner</b>  Lee, Shun	<b>Art Unit</b>  2884

SEARCHED			
Class	Subclass	Date	Examiner
250	370.01	6/16/2006	/SL/
250	370.06	6/16/2006	/SL/
250	370.13	6/16/2006	/SL/
Above	UPDATED	3/20/2007	/SL/
Above	UPDATED	10/3/2007	/SL/
Above	UPDATED	4/10/2008	/SL/
Above	UPDATED	1/6/2011	/SL/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	1/6/2011	/SL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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